1.	Record Nr.	UNINA9910827678303321
	Titolo	Cluster secondary ion mass spectrometry : principles and applications / / edited by Christine M. Mahoney
	Pubbl/distr/stampa	Hoboken, N.J., : John Wiley & Sons, Inc., 2013
	ISBN	9781118589243 1118589246 9781118589335 1118589335 9781299475878 1299475876 9781118589250 1118589254
	Edizione	[1st ed.]
	Descrizione fisica	1 online resource (366 p.)
	Collana	Wiley Series on Mass Spectrometry
	Altri autori (Persone)	MahoneyChristine M
	Disciplina	543/.65
	Soggetti	Secondary ion mass spectrometry Mass spectrometry
	Lingua di pubblicazione	Inglese
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
	Note generali	Description based upon print version of record.
	Nota di bibliografia	Includes bibliographical references and index.
	Nota di contenuto	CLUSTER SECONDARY ION MASS SPECTROMETRY; CONTENTS; Contributors; About the Editor; 1 AN INTRODUCTION TO CLUSTER SECONDARY ION MASS SPECTROMETRY (CLUSTER SIMS); 1.1 Secondary Ion Mass Spectrometry in a Nutshell; 1.1.1 SIMS Imaging; 1.1.2 SIMS Depth Profiling; 1.2 Basic Cluster SIMS Theory; 1.3 Cluster SIMS: An Early History; 1.3.1 Nonlinear Sputter Yield Enhancements; 1.3.2 Molecular Depth Profiling; 1.4 Recent Developments; 1.5 About this Book; Acknowledgment; References; 2 CLUSTER SIMS OF ORGANIC MATERIALS: THEORETICAL INSIGHTS; 2.1 Introduction 2.2 Molecular Dynamics Simulations of Sputtering with Clusters2.2.1 The Cluster Effect; 2.2.2 Computer Simulations and the Molecular Dynamics ""Experiment""; 2.2.3 Light and Heavy Element Clusters, and the Importance of Mass Matching; 2.2.4 Structural Effects in Organic Materials; 2.2.4.1 Amorphous Molecular Solids and Polymers; 2.2.4.2 Organic Crystals; 2.2.4.3 Thin Organic Layers on Metal Substrates;

Sommario/riassunto	Explores the impact of the latest breakthroughs in cluster SIMS technology Cluster secondary ion mass spectrometry (SIMS) is a high spatial resolution imaging mass spectrometry technique, which can be used to characterize the three-dimensional chemical structure in complex organic and molecular systems. It works by using a cluster ion source to sputter desorb material from a solid sample surface. Prior to the advent of the cluster source, SIMS was severely limited in its ability to characterize soft samples as a result of damage from the atomic source. Molecular samples were es